

The NA48/3 GigaTracker

Alias

Tracking in the beam
at 1GHz rate

- GigaTracker: Decay ID & bkg rejection
- Requirements
- In the beam
- Resolution & material budget
- Rate & dose
- Time resolution

K Rare decays meeting, Frascati 26-27.05.2005

M. Scarpa INFN and University of Ferrara

Decay ID

0.8-1GHz beam (2.5×10^9 ppp/3s

spill +20% error)

60% π^+

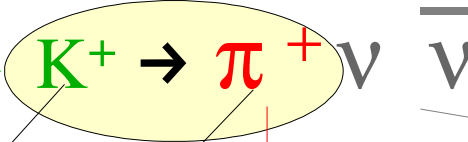
20% p^+

14% e^+

6% K^+

Beam
CEDAR,GT

Decay products
NA48/3 detector



• Missing mass

- 1! detected decay product
- no vertex from decay product

75GeV/c $\sigma(p)/p = 1\%$ $\sigma_x \sim 8\text{mm}, \sigma_y \sim 1.1\text{mm}$

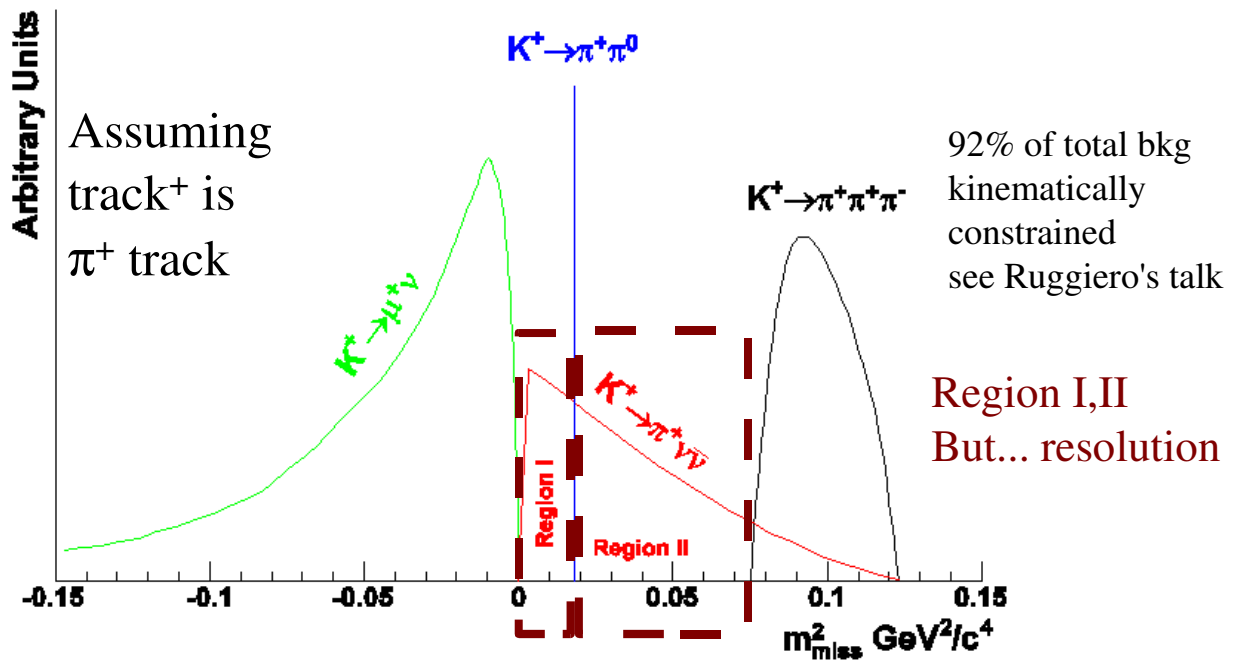
angular spread $\sigma(\theta) = 100\mu\text{rad}$

↪ need more precise momentum and direction measurements ↪ GigaTracker

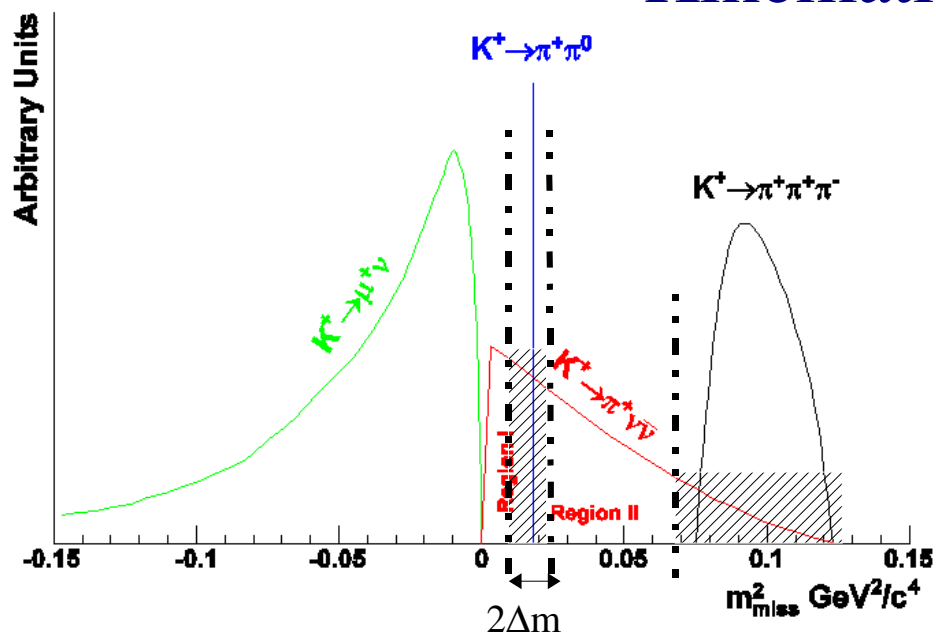
$$m_{\text{miss}}^2 = m_{\pi}^2(1 - P_K/P_{\pi}) + m_K^2(1 - P_{\pi}/P_K) - P_K P_{\pi} \theta_{K\pi}^2$$

Decay ID:

- K, π ID
- $K-\pi$ tracks matching vtx
- P_K, P_{π}
- $\theta_K, \theta_{\pi} \rightarrow \theta_{K\pi}$
- VETOes



Kinematical bkg rejection



$$\text{RI} : 0 < m^2_{\text{miss}} < m^2_{\pi\pi} - \Delta m$$

$$\text{RII} : m^2_{\pi\pi} + \Delta m < m^2_{\text{miss}} < \min(m^2_{3\pi}) - \Delta m$$

$$\Delta m \div \sigma(m^2_{\text{miss}})$$

Worse $\sigma(m^2_{\text{miss}}) \Rightarrow$ lower S/B

K- π tracks matching e.g by best CDA

Beam at GT:

$\sigma_x \sim 8\text{mm}, \sigma_y \sim 1.1\text{mm}$

100 μrad angular spread

$\sim 70\mu\text{rad}(x), 85\mu\text{rad}(y)$

Beam track/s (GT)

best CDA

closest distance

of approach $\sigma_{\text{CDA}} \sim 1.4\text{mm} (*)$

\Downarrow Downstream track (double spectrometer)

IF 1 track matching in GT
 $\sigma(m^2_{\text{miss}})$ tiny \Rightarrow S/B ~ 100

(* MC detail see next slide)

IF **>1 track** in GT matching (8.6% events *)
 $\sigma(m^2_{\text{miss}}) \sim 3.5(*)$ times bigger \Rightarrow S/B degradation
 Keep the events & **add time constraints**

Requirements on GT from

The experiment:

- Acceptance 10% (50% data taking efficiency included)
- S/B ≥ 10

The beam:

- Beam K^+ 75GeV/c **momentum bite 1%**
- @GT $\sigma_x \sim 8\text{mm}, \sigma_y \sim 1.1\text{mm}$
- minimum amount of material on beam $X/X_0 \ll 1\%$
- Tracking in a not uniform (converging beam) rate distribution
- total rate of $\sim 1\text{GHz}$ out of which only $\sim 6\%$ are K^+
- High radiation level

The MC study on $\pi^+\pi^0$
assuming

- photon rejection inefficiency 2×10^{-8}
- $(15 < P_\pi < 35)\text{GeV}/c$

- Hodoscope event time $\sigma(t) \sim 50\text{ps}$
- Double spectrometer: straws $\sim 0.5\% X_0$ per chamber,
spatial resolution $120\mu\text{m}$ per view
100% reconstruction efficiency,

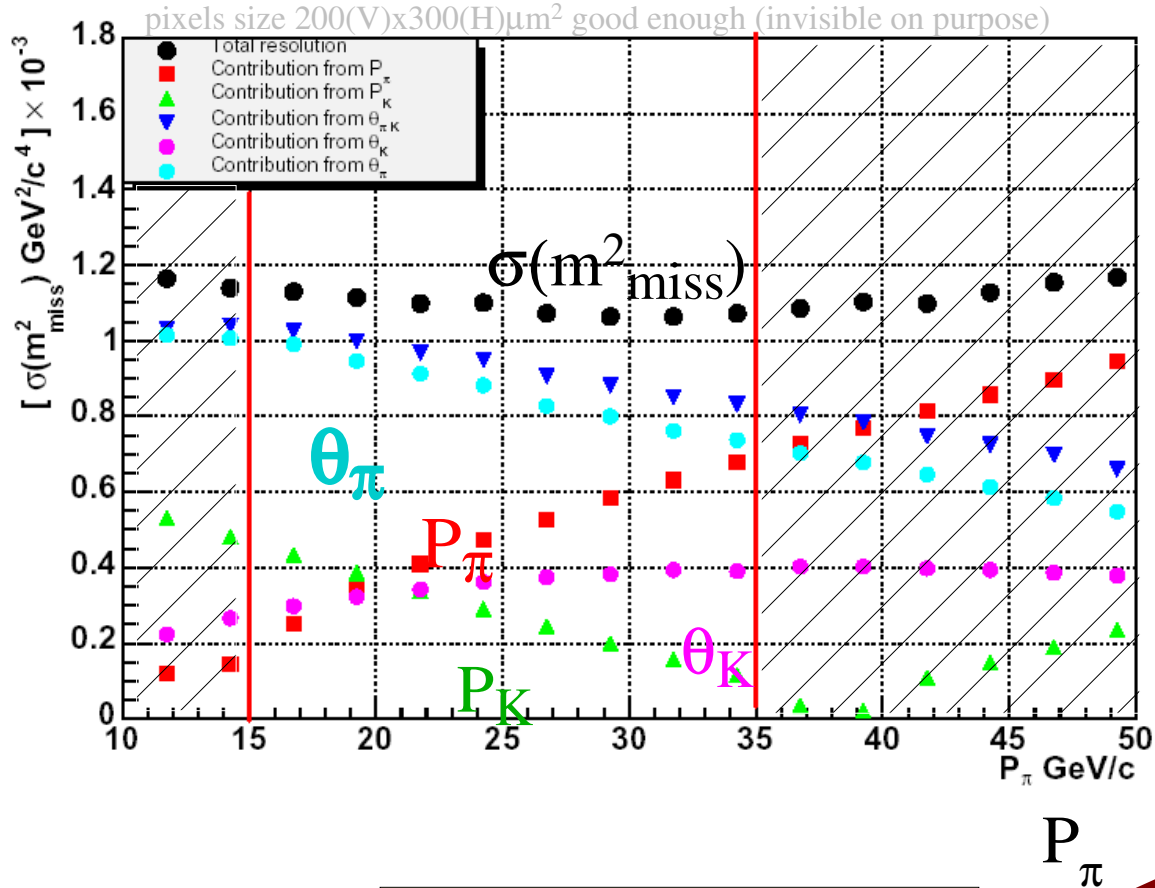
⇒ **Double spectrometer** $\sigma(p)/p = 0.33\% \oplus 0.0077\% p$, $\sigma(\theta)$ in X and Y projections $\sim 30\mu\text{rad}$
not spoil the spectrometer angular measurements: minimize MS in the last part of GT

with **GT**: $\sigma(p)/p = 0.3\%$, $\sigma(\theta)$ in X and Y projections $\sim 15\mu\text{rad}$

- ⇒ $\sim 8.6\%$ events have >1 track matching in GT with bestCDA(*) approach, reducible to $\sim 3\%$ by time coincidence in $\pm 2\sigma(t)_{\text{GT}}$ **IF** $\sigma(t)_{\text{GT}} = 100\text{ps}$ ⇒ S/B ~ 25

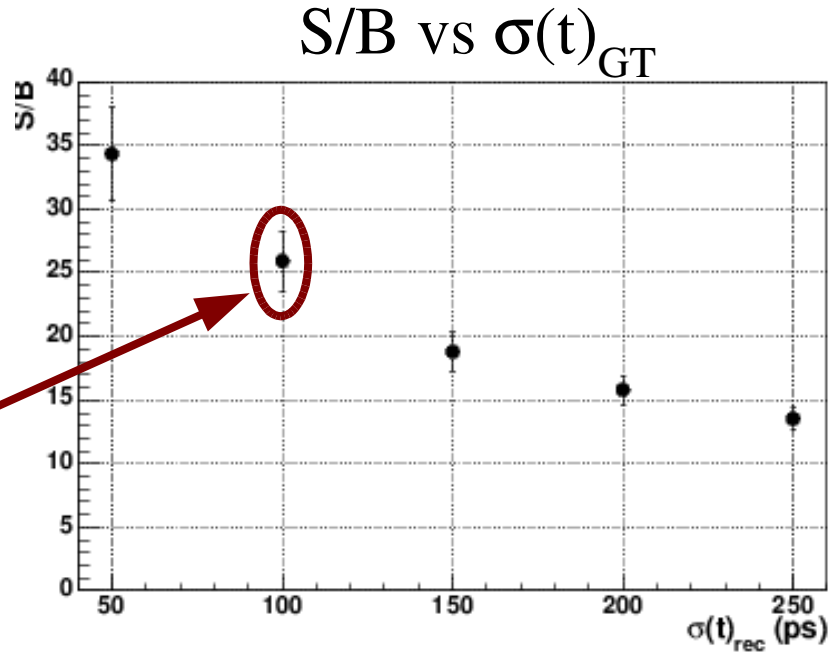
(*) might be improved by other matching methods e.g. 2D impact parameter

MC Requirements on GT

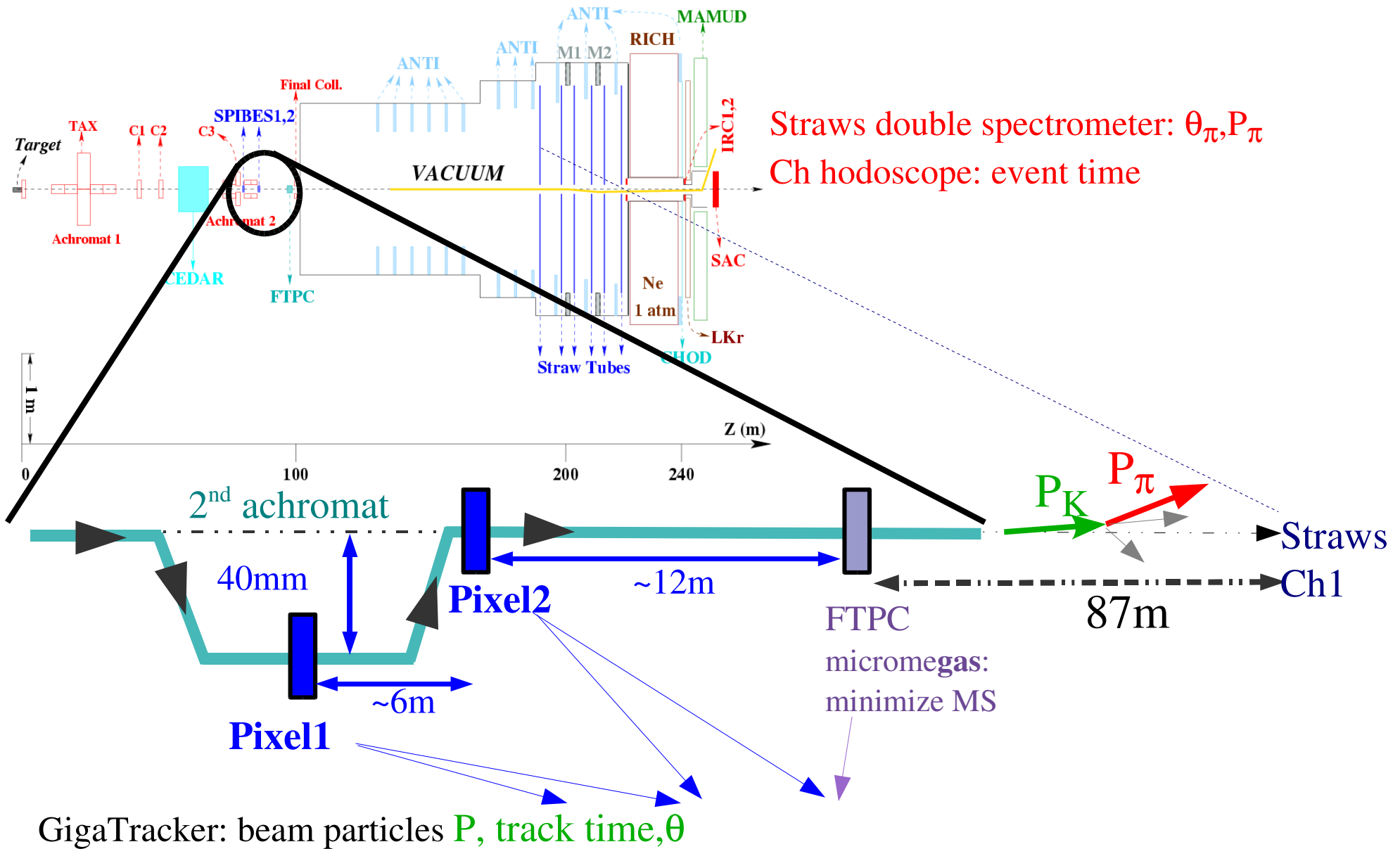


GT:

- $\sigma(p)/p = 0.3\%$ ($<0.5\%$)
- $\sigma(\theta_{x,y}) \sim 15\mu\text{rad}$
- $\sigma(t)_{\text{GT}} = 100\text{ps}$ on the track



In the beam with GT



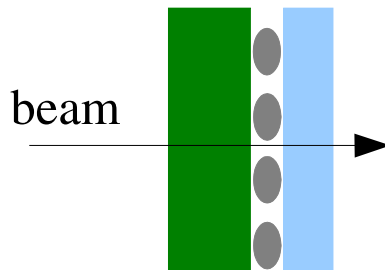
Resolution and material budget

Station 1 and 2: hybrid Silicon pixels

- Minimize material on beam
- produce signals, fast signals
- electronics
- cooling
- support
- respecting the NA48/3 requirements and timescale



- Hybrid Silicon ($X_0=9.36\text{cm}$) pixel detectors:
Silicon sensor bump bonded ($\sim 0.01\% X_0$) to
Silicon chip



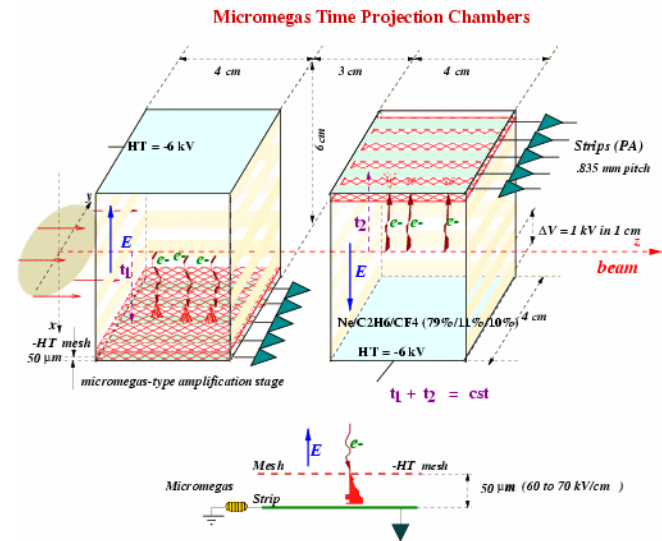
- cooling & support with the same CFiber
- In vacuum (save $100\mu\text{m}$ mylar windows front and back: $0.7\% X_0$) -> cooling by conduction

Station 3: FlashTPC

Minimize MS effect on downstream detector measurements (especially angle)

TPC with micromegas amplification
 Upgraded version of Kabes-NA48/2:

- position resolution $80\mu\text{m}$
- $\sigma_t = 0.7\text{ns}$
- max strip rate $\sim 2\text{MHz}$



Reduce the amplification gap, sampling each strip with 1GHz FADC, sustain 10x higher rate per unit area

Pixel stations material budget

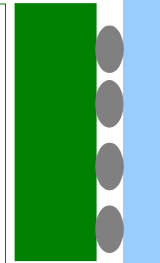
% X_0 per station mainly due to Silicon:

	μm	X_0 (cm)	% X_0
Si det+chip	200+100	9.36	0.32
CFiber	125	22.4	0.06
bb(SnPb)			0.01
(Mylar windows no if in vacuum			0.07)

			~0.4

Coulomb MS $\theta_{\text{rms}} \sim 13\text{mrad}$ 

Silicon
sensor
produces
the signal!



Silicon on chip side
is mostly a support

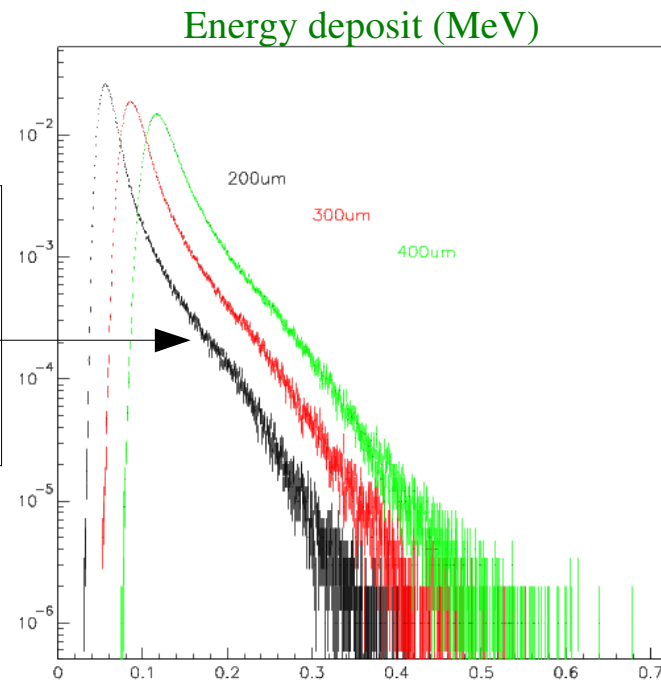


try to reduce it to
100 μm (fragility!)

Sensor with thickness down
to 200 μm already produced
and bump bonded e.g. Alice SPD

200 μm thick Si signal:
peak @ 55KeV ~ 15Ke-/holes
mean 68KeV ~ 19Ke-/holes
min ~ 11Ke-/holes
(but 0.5% low energy tail)

Geant4 v6.2
 10^6 75GeV K+
all secondary processes on
5 μm cuts



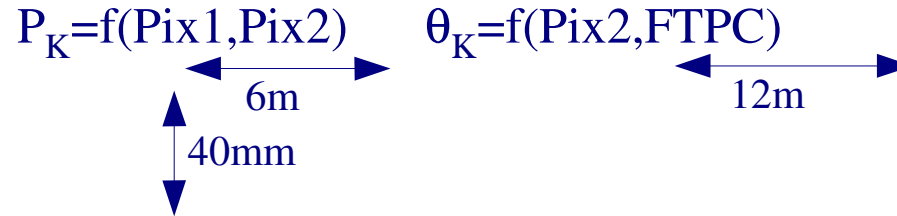
R/o chip wafers thinned down
to 150 μm already exist: Alice SPD



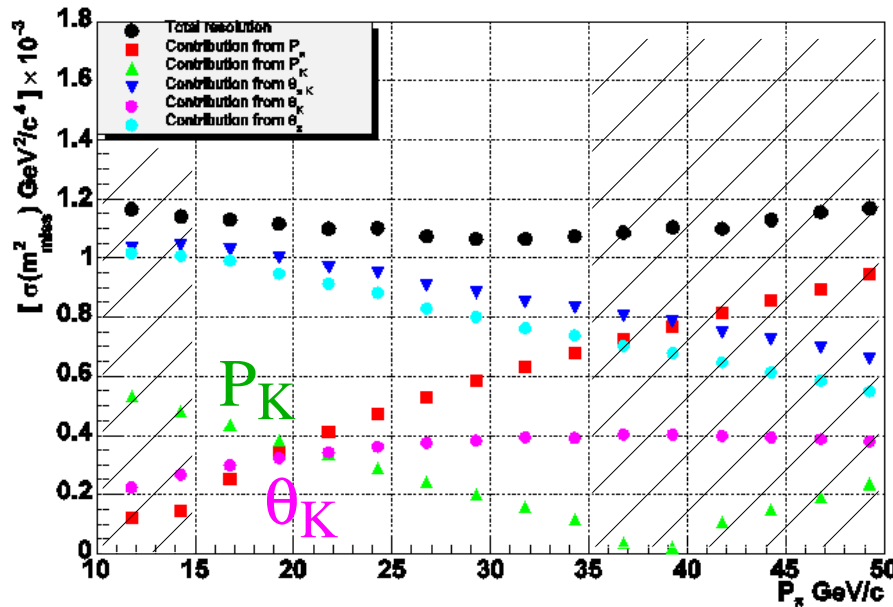
J. Salmi/ VTT

Present at ion at BOND'03 workshop, CERN, June 2003

Pixel size and resolutions



x,y dim (μm)	$\sigma_{x,y}$ (μm)	$\sigma(P)/P$ % $(\sigma_y \sqrt{2} \oplus \sigma_{\text{MS}})/40\text{mm}$	σ_θ (μrad) $(\sigma_x \oplus \sigma_{\text{FTPC}})/12\text{m} \oplus \sigma_{\text{MSP}}$
100	29	0.22	14.7 , if Pixel3 13.4
200	58	0.29	15.3 14.6
300	87	0.37	16.4 16.4

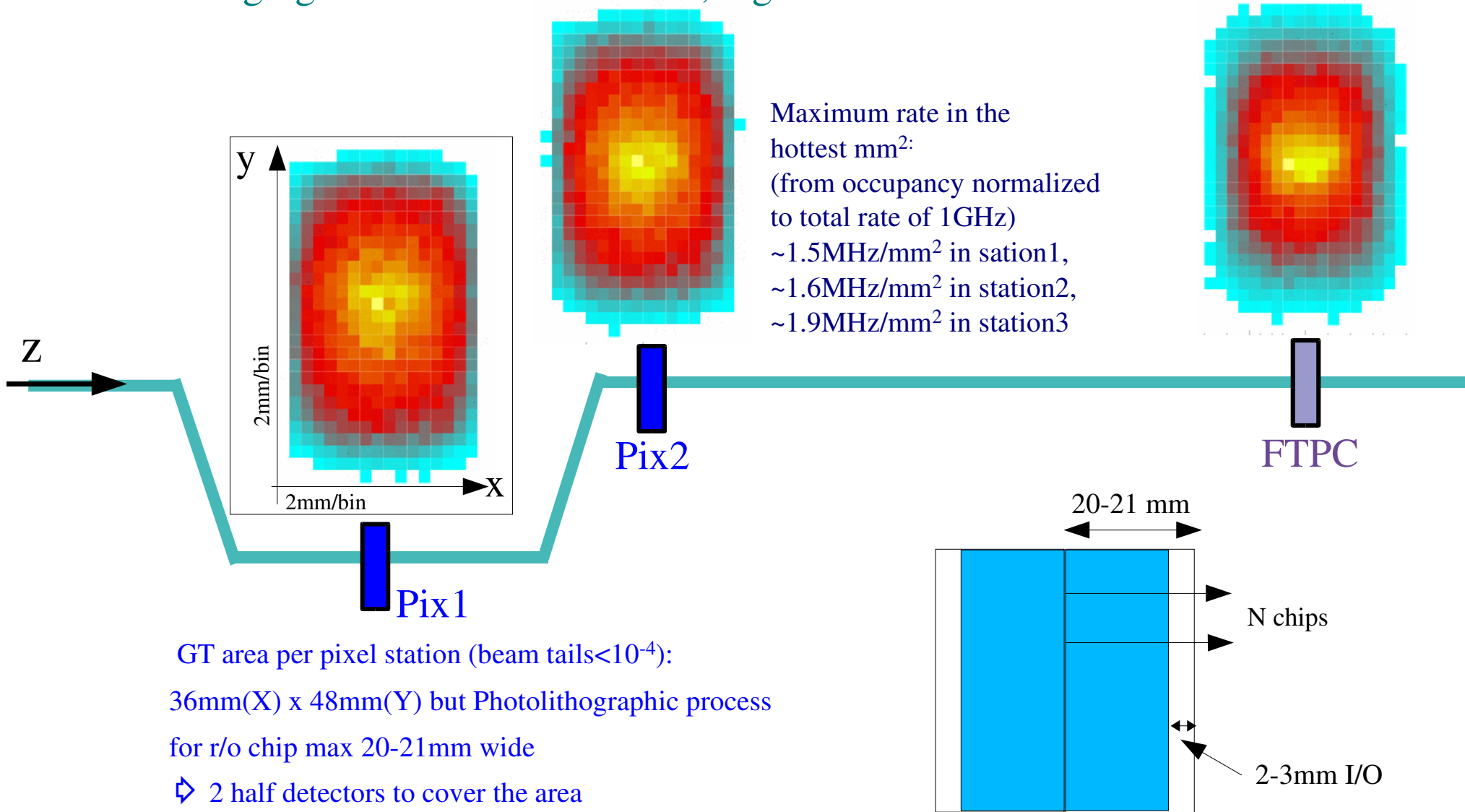


MC simulation: 3 stations
 0.4% X_0 per station
 pixel 200(V)x300(H) μm^2
 good enough

Rate and radiation at GigaTracker I

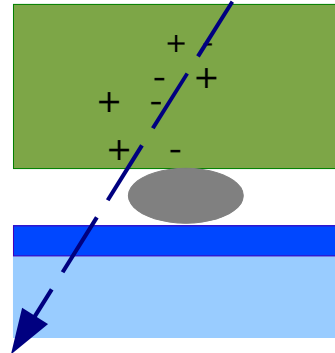
Average rate per station $\sim 60\text{MHz}/\text{cm}^2$

Converging beam: rate not uniform, higher rate in the center



Rate and radiation at GigaTracker II

Radiation damage on pixels detector



CMOS readout chip:
sensitive components
close to the surface

- Total Ionizing Dose (TID)
ionization in SiO_2 layer and
defects creation SiO_2 -Si interface
⇓
 - transistor level leakage (mainly digital)
 - ⇓ enclosed transistors
 - threshold voltage shift (analogue)
 - ⇓ sub-micron tech e.g. $0.25\mu\text{m}$ or $0.13\mu\text{m}$
(the thinner the oxide the best)
- Single Event Upset (SEU) (reversible) affecting bit
 - ⇓ redundancy e.g. cells x3 & major voting
or special coding schemes

Sensor: full bulk sensitive to damage

Bulk damage



change electrical characteristics, evolves with time and
doesn't stop when stopping irradiation

- Increase $I_{\text{leak}} \div \exp(-E_{\text{gap}}/2KT)$ due to
generation/recombination levels
- ⇓ cooling, thinner sensor, sensor technology and design

● Change in V_d (depletion voltage):
type 'inversion': n-type bulk behave like p-type, depletion from backside and V_d increase with
fluence, risk to operate with under-depleted sensor:
charge loss and spread. Too high voltages --> current
break down

- Annealing effect (beneficial and reverse)
long term exposition , temperature dependent

Rate and radiation at GigaTracker III

Per GT station in NA48/3 beam the expected
average particle flux/cm² per day is:

$$1\text{GHz} \cdot 3.125\text{s}(\text{eff spill}) \cdot 5000(\text{spills/day}) / \text{area} \sim 9 \times 10^{12} \text{ particles/cm}^2\text{day}$$

- Approx π only beam (60%)
- conversion factor 0.37 ratio of displacement damage cross sections for high energy (>GeV) π (35MeV mb) and 1MeV neutron (95MeV mb) (Huhtinen private communication, NIMA491)
- safety factor 2

⇒ Φ_{eq} (1MeV n)/cm²

$\sim 7 \times 10^{11}$ day
 7×10^{13} **100 days**
x3 in the hottest mm²

1MeV equiv n/cm²: norm fluence unit used to compare real beam with 1MeV n beam producing the same displacement damage

3×10^{14} **CMS innermost pixels in 1 year**
 3×10^{12} **ALICE pixels in 10 years**

1-few $\times 10^{12}$ expected n-type-inversion point



Replace the pixel stations every 2 weeks (profiting of SPS MD)
⇒ **easy replacement and alignment**

and an **average TID (rad) $\sim 2\text{Mrad}$ in 100 days** (2 yrs data taking)

R/O chip: up to TID=30Mrad with radiation tolerant layout (vast majority LHC experiment):

0.25 μm CMOS + enclosed + guard rings

(IEEE Vol.46 No.6 1999, G.Anelli Ph.D Thesis <http://rd49.web.cern.ch/RD49/RD49Docs/anelli/these.html>)

Time resolution requirement I

- Requirement on spatial resolutions: easy with Si pixels + FTPC
- Requirement on material budget: easy FTPC, pixels less easy but feasible
 - investigation on chip silicon thickness
 - investigation on CF support and cooling (depends on chip consumption)

● Requirements on time resolution: 100ps on the track

⇒ ~150ps per pixel station(TDC)

high complexity R/O CHIP bump bonded on sensor

- on beam (radiation hardness technology --> space)
- analogue AND digital high frequency part together:

influence of the noisy digital part on the analogue part

Switching noise originated from the digital circuits can be coupled in the analog part through power and ground lines, parasitic capacitances between interconnection lines and, the most difficult to eliminate, common substrate noise

Building blocks: fast preamplifier and shaper,

low time walk discriminator,

high resolution TDC,

peripheral circuitry

- power dissipation
- technology CMOS process: 250nm might be insufficient ⇒ 130nm

Time resolution requirement II

Very challenging but good hints from TCAD simulations of 200 μm thick sensor:

few ns charge collection time achievable using n or p substrates

Simulation on 'a la' ALICE pixels: 50(V)x425(H) μm^2

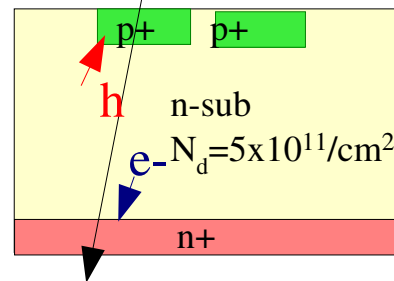
Pixels 50(V)x425(H) μm^2 , 200 μm thick



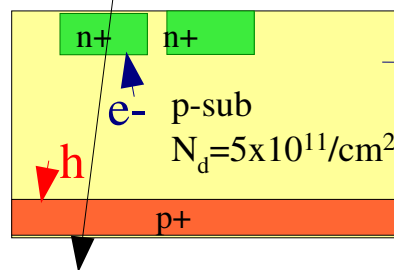
small pixel wrt thickness \Rightarrow signal mainly determined by

- ① p+ on n-type substrate: holes
- ② n+ on p-type substrate: e-

①

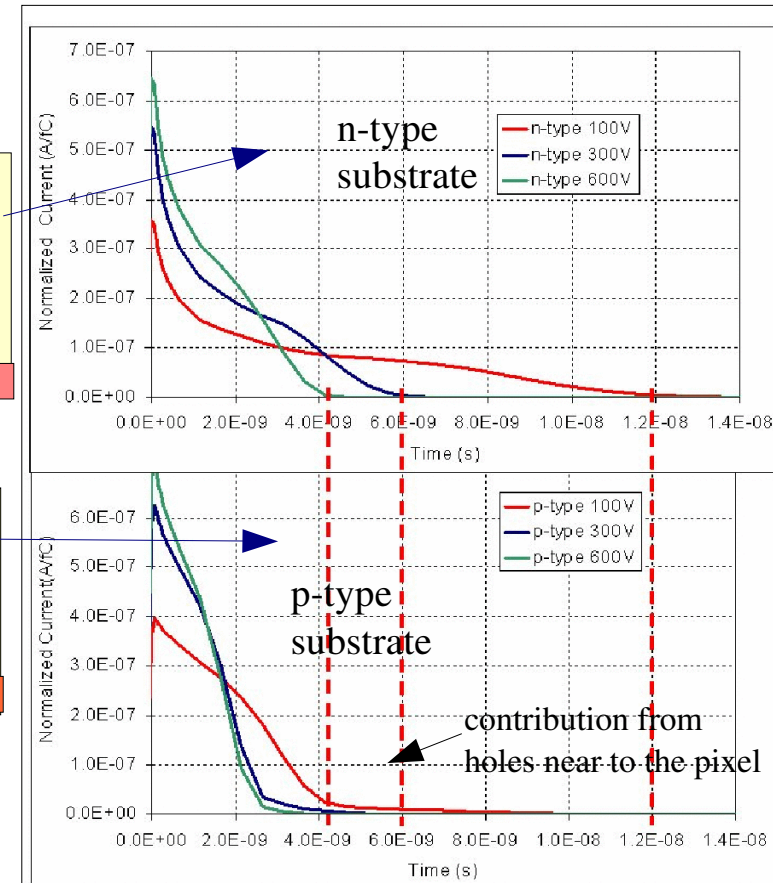
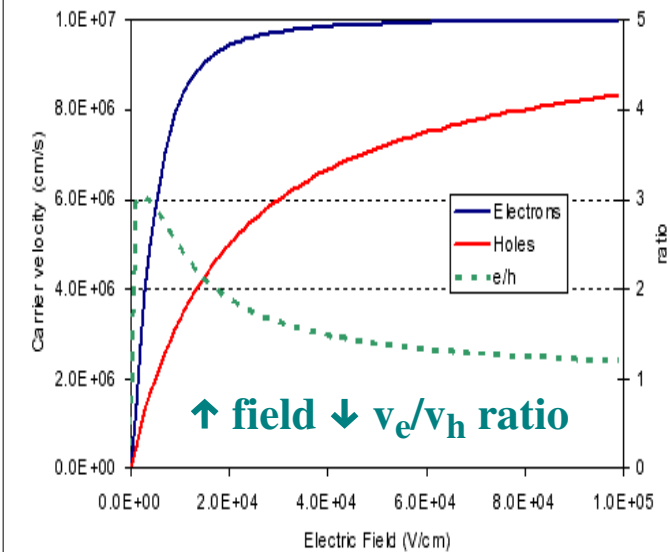


②



\uparrow pixel size 'a la' GT \uparrow tails
 \Rightarrow n and p substrate \sim same collection time

Carrier velocity



TCAD simulation
 Claudio Piemonte, ITC-IRST

Conclusions

GigaTracker: 2 pixels stations + 1FTPC
for tracking @1GHz rate IN THE BEAM
with excellent

spatial (good if 200(V)x300(H) μm^2 pixel and $\sigma= 80\mu\text{m}$ FTPC)
AND time resolutions (100ps on the track \Rightarrow 150ps per TDC)

FTPC upgrade

New Pixel stations

- sensor (tests to be done, 'easiest' part wrt r/o chip)
few ns collection time achievable with both p and n substrates
- readout chip (challenging)
- cooling (chip power dissipation)
- support & alignment (frequent replacement)

Be ready for data taking in 2009